

Notice of References Cited	Application/Control No. 10/525,766	Applicant(s)/Patent Under Reexamination HORIKAWA ET AL.	
	Examiner Linh T. Nguyen	Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0090981	05-2003	Yokoi, Kenya	369/59.11
*	C	US-2006/0245328	11-2006	Ahn et al.	369/059.11
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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